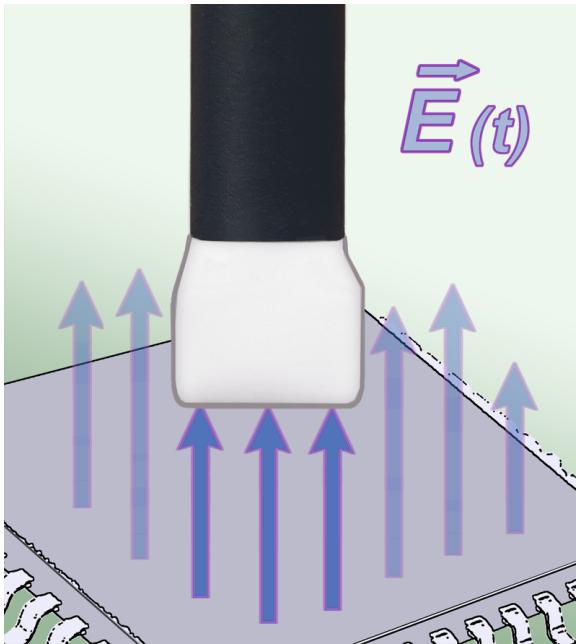


RF-E 04

E-Field Probe 30 MHz up to 3 GHz

LANGER
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Short description

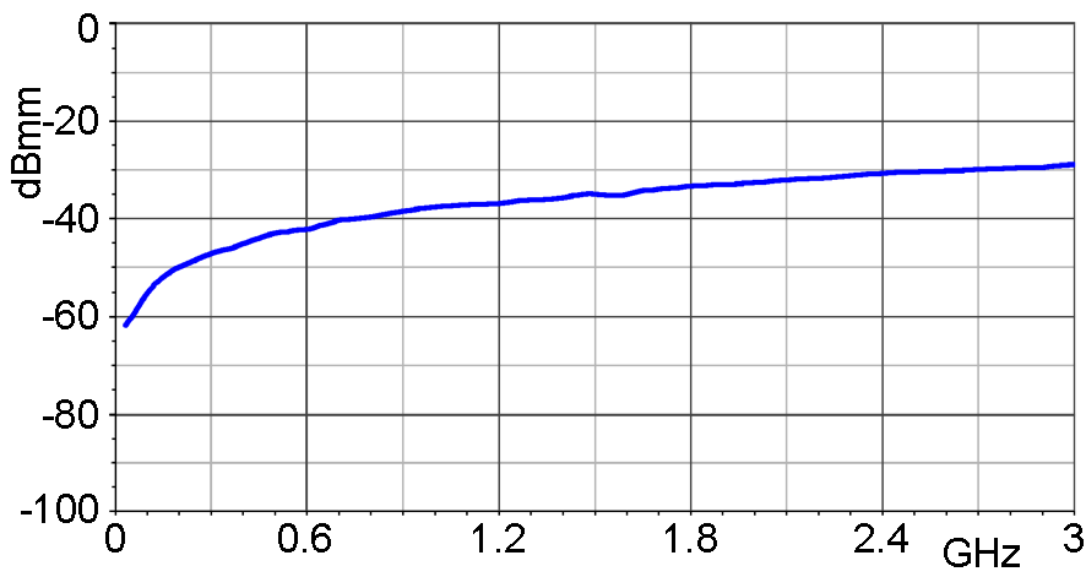
The electrode on the underside of RF-E 04 probe head detects electrical fields which are decoupled by clocked lines and ICs. The resolution of the probe allows for measurements with a distance from 0,5 to 10 mm above the assembly. The RF-E 04 probe was developed for Langer scanner.

The RF-E 04 is a passive near-field probe. In principle it has the same structure as the RF-E 03 and RF-E 09 probes. With its small square electrode surface, the specific source of the electrical interference field can be detected. When measuring, the E-field probe is held above or positioned onto components and printed circuit boards. The near-field probe is small and handy. The upperside is electrically shielded. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E-field probe does not have an internal terminating resistance of 50 Ω .

Technical parameters

Frequency range	30 MHz ... 3 GHz
Probe head dimensions	$\approx (5 \times 5)$ mm
Connector	SMB, male, jack

Frequency response

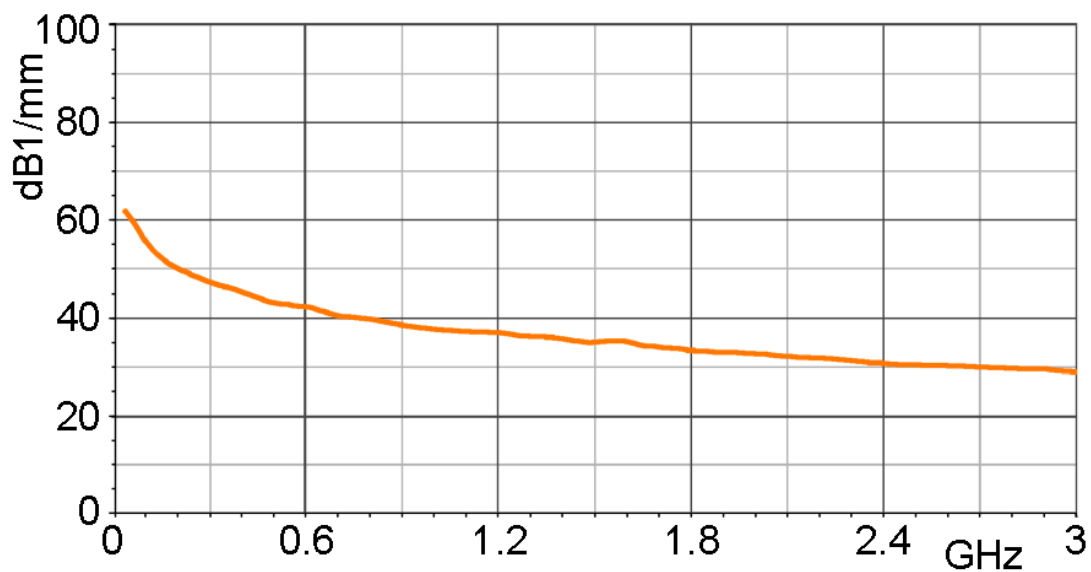


RF-E 04

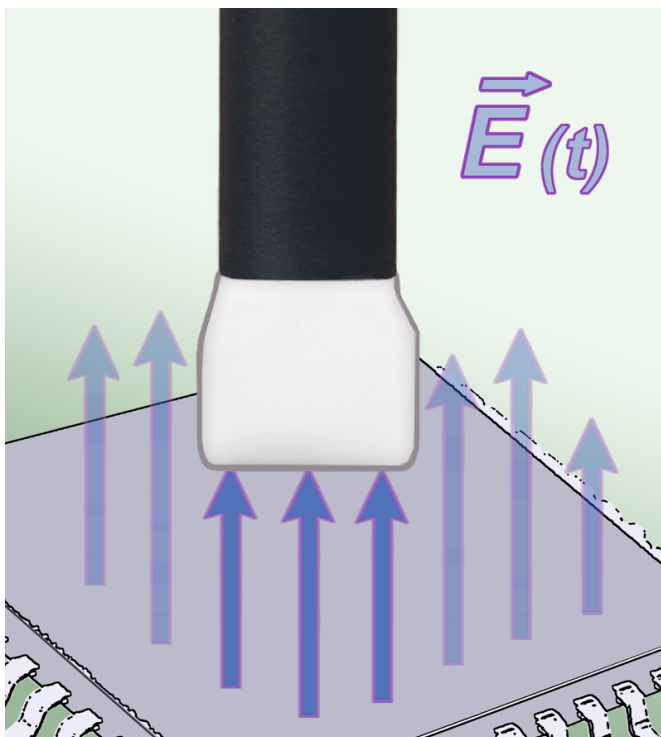
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E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



RF-E 04

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Probe head

